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捷多邦,专业PCB打样SN54ACT573出SN74ACT573 **OCTAL D-TYPE TRANSPARENT LATCHES** WITH 3-STATE OUTPUTS SCAS538C - OCTOBER 1995 - REVISED JANUARY 2000

- Inputs Are TTL-Voltage Compatible
- **EPIC[™]** (Enhanced-Performance Implanted CMOS) 1-µm Process
- **Package Options Include Plastic** Small-Outline (DW), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPs

description

These 8-bit latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. The devices are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight latches are D-type transparent latches. When the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the logic levels set up at the D Inputs.

A buffered output-enable (OE) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines in a bus-organized system without need for interface or pullup components.

SN54ACT573 J OR W PACKAGE
SN74ACT573DB, DW, N, OR PW PACKAGE
(TOP VIEW)

	_		_	
OE [1		0	Vcc
1D [2	1	9	1Q
2D [3	1		2Q
3D [4	1		3Q
4D [5	1	6	4Q
5D [6	1	5	5Q
6D [7	1	4	6Q
7D [8	1	3	7Q
8D [9	1	2	8Q
gnd [10	1	1	LE

SN54ACT573 ... FK PACKAGE (TOP VIEW)

2D 2D 2D 2D 2D
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$

OE does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ACT573 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ACT573 is characterized for operation from -40°C to 85°C.

	FUNCTION TABLE (each latch)											
		OUTPUT										
	OE	LE	D	Q								
	L	н	Н	Н								
1	0.3	н	L	L								
2	L	L	Х	Q ₀								
	Н	Х	Х	z								
				_								



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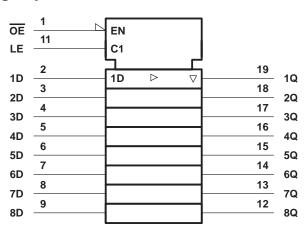


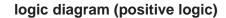
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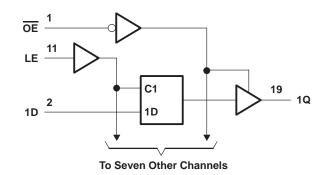
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logic symbol[†]







[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

PW package	Supply voltage range, V_{CC} Input voltage range, V_I (see Note 1) Output voltage range, V_O (see Note 1) Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$) Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$ Continuous output current, I_O ($V_O = 0$ to V_{CC}) Continuous current through, V_{CC} or GND Package thermal impedance, θ_{JA} (see Note 2):	C) C) DB package DW package N package	$\begin{array}{c} -0.5 \ \mbox{V to } \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ $
5	Storage temperature range, T _{stg}		

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

2. The package thermal impedance is calculated in accordance with JESD 51.



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recommended operating conditions (see Note 3)

		SN54ACT573		SN54ACT573 SN74ACT573		
		MIN	MAX	MIN	MAX	UNIT
VCC	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
VIL	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	VCC	0	VCC	V
Vo	Output voltage	0	VCC	0	VCC	V
ЮН	High-level output current		-24		-24	mA
IOL	Low-level output current		24		24	mA
$\Delta t/\Delta v$	Input transition rise or fall rate	0	8	0	8	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics	over	recommended	operating	free-air	temperature	range	(unless
otherwise noted)					-	•	

DADAMETER		Vcc	T,	T _A = 25°C			CT573	SN74A	LINUT	
PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
	I _{OH} = -50 μA	4.5 V	4.4	4.49		4.4		4.4		
	$10H = -30 \mu\text{A}$	5.5 V	5.4	5.49		5.4		5.4		
Maria	I _{OH} = – 24 mA	4.5 V	3.86			3.7		3.76		V
VOH	IOH = -24 IIIA	5.5 V	4.86			4.7		4.76		v
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	I _{OH} = -75 mA [†]	5.5 V						3.85		
	1	4.5 V			0.1		0.1		0.1	
	I _{OL} = 50 μA	5.5 V			0.1		0.1		0.1	
Max	I _{OL} = 24 mA	4.5 V			0.36		0.44		0.44	V
VOL		5.5 V			0.36		0.44		0.44	V
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65			
	I _{OL} = 75 mA [†]	5.5 V							1.65	
I _{OZ}	$V_{O} = V_{CC} \text{ or } GND$	5.5 V			±0.25		±5		±2.5	μΑ
lj	V _I = V _{CC} or GND	5.5 V			±0.1		±1		±1	μA
ICC	$V_{I} = V_{CC} \text{ or GND}, \qquad I_{O} = 0$	5.5 V			4		80		40	μA
$\Delta I C C^{\ddagger}$	One input at 3.4 V, Other inputs at GND or V _{CC}	5.5 V		0.6			1.5		1.5	mA
Ci	V _I = V _{CC} or GND	5 V		5						pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

		T _A = 25°C		T _A = 25°C		T _A = 25°C SN54ACT573		SN74A	UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT	
tw	Pulse duration, LE high	3.5		5		4		ns	
t _{su}	Setup time, data before LE \downarrow	3		4.5		3.5		ns	
th	Hold time, data after LE \downarrow	0		1		0		ns	



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switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	Т	₄ = 25°C	;	SN54A	CT573	SN74A	CT573	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	D	Q	2.5	6	10.5	1.5	13.5	2	12	ns
^t PHL	D	9	2.5	6	10.5	1.5	13.5	2	12	115
^t PLH	LE	Q	3	6	10.5	1.5	13	2.5	12	ns
^t PHL		9	2.5	5.5	9.5	1.5	12	2	10.5	115
^t PZH	05	Q	2	5.5	10	1.5	11.5	1.5	11	ns
^t PZL	OE	9	1.5	5.5	9.5	1.5	11	1.5	10.5	115
^t PHZ	ŌĒ	Q	2.5	6.5	11	1.5	13.5	1.5	12.5	ns
^t PLZ	UE	3	1.5	5	8.5	1.5	10.5	1	9.5	115

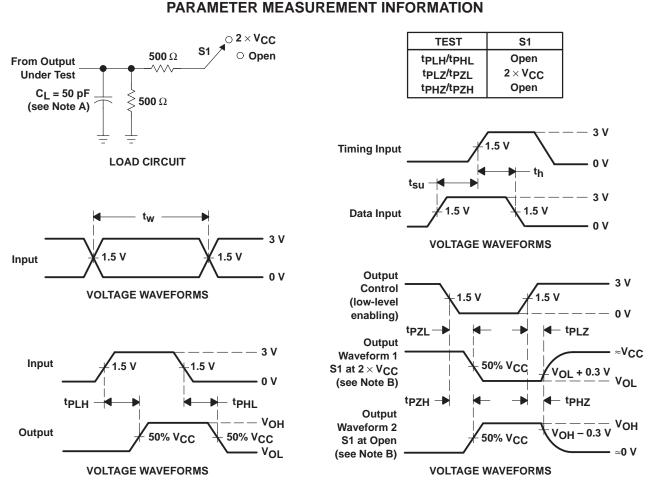
operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CO	NDITIONS	TYP	UNIT
Cpd	Power dissipation capacitance	C _L = 50 pF,	f = 1 MHz	25	pF



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NOTES: A. $C_{\mbox{L}}$ includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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